

Notice of References Cited

Application/Control No.

09/992,318

Applicant(s)/Patent Under Reexam

Maccarone

Examiner

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Art Unit

2859

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¹ A copy of this reference is not being furnished with this Office action. See MPEP § 707.05(a).¹ Dates in MM-YYYY format are publication dates.² Classifications may be U.S. or foreign.